

A Procedure for Highly Reproducible Measurements of ADC Spectral Parameters

Emilia Nunzi, Paolo Carbone, *Associate Member, IEEE*, and Dario Petri, *Member, IEEE*

Abstract—The evaluation of spectral parameters characterizing analog-to-digital converters (ADCs) is addressed by applying a single- or dual-tone generator to the device input and by properly processing its output data stream. The coherent sampling condition, highly recommended by the IEEE standards 1057 and 1241 which list the most effective ADC testing procedures, is usually difficult to achieve, and sometimes even unfeasible. In fact, it requires a fine synchronization between the input and the sampling signals frequencies and it cannot be achieved when spurious tones are present in the ADC output spectrum. Data windowing is usually employed to reduce the associated spectral leakage phenomenon. However, IEEE standards do not provide clear criteria for choosing the window to be used for testing a given b -bit converter. Therefore, a reduced measurement reproducibility can result. The European draft standard Dynad suggests the employment of one out of seven windows in accordance to the ADC resolution. However, each proposed sequence covers only a limited converter resolution range. In this paper, an ADC testing procedure is described, suitable to yield highly repeatable and reproducible measurements, also when noncoherent sampling applies. To this aim, the use of a class of windows is proposed, that uniquely applies to ADCs with arbitrarily high resolution. Finally, experimental results that validate its effectiveness are presented.

Index Terms—Digitizer fast Fourier transform (FFT) test, discrete prolate spheroidal sequence (DPSS) windows, FFT test procedure.

I. INTRODUCTION

METHODOLOGIES usually employed for the parameter estimation of analog-to-digital converters (ADCs) are based on the analysis of the ADC numerical output when a single or dual tone is used as input signal [1], [2]. The observed ADC output data can be often modeled as a set of single-tone components embedded in white zero-mean Gaussian noise. Therefore, the problem of evaluating the ADC frequency-domain performance reduces to the estimation of multiple sine parameters and of the broad-band noise-level.

Such an estimation problem, widely investigated and detailed in the scientific literature, can be addressed by employing both parametric or nonparametric procedures [3]–[6]. Although parametric procedures present an high frequency selectivity and statistical efficiency, the determination of the model order is often a difficult issue and iterative procedures must be used. Conversely, nonparametric testing procedures are characterized by low computational effort and robustness toward

signal model inaccuracies. On the other hand, they present lower frequency selectivity and statistical efficiency [4], [5]. However, such performances reduction can be compensated for by increasing the observation interval length or the number of analyzed samples. Thus, nonparametric procedures can be widely applied for waveform digitizer testing.

Whatever the adopted testing methodology, the IEEE standards 1057 and 1241 [1], [2] recommend the use of coherent sampling in order to guarantee maximum estimation accuracy. However, such a condition can not be guaranteed with respect to spurious tones eventually present in the output spectrum. In such a situation, spectral granularity and leakage may affect the accuracy with which input signal parameters are estimated. Output-data windowing has been classically employed to reduce the effect of such phenomena [3]. Unfortunately, published results do not provide general criteria for the choice of the most appropriate window to be employed. Some suggestions are given in the draft standard Dynad [7], where it is recommended the selection of one out of well-known windows [3], in accordance to the resolution of the tested ADC. However, criteria to be followed for choosing the window that optimizes measurement accuracy are not explicitly given.

Previous works on this subject have shown that the employment of the zero-order discrete prolate spheroidal sequences (DPSSs) maximizes the measurement accuracy when noncoherent sampling applies [4], [9]. Windows belonging to this class of sequences are completely defined by their mainlobe width. Moreover, general criteria for selecting the window parameter that provides a given estimation accuracy for ADCs with any resolution have been given. This feature allows the optimization of the window selection process, thus improving testing automation. However, samples of the DPSS windows can be calculated only on the basis of numerical algorithms. As a consequence, different implementations applied to the same set of data can result in different estimates of ADC figures of merit, thus reducing measurement reproducibility.

In this paper, the use of a class of windows that can easily be calculated by using standard computational tools and that well approximates the DPSS sequences is proposed. In particular, such windowing sequences are employed in a discrete Fourier transform (DFT)-based estimator of the main spectral figures of merit of a generic b -bit ADC. The algorithm is then detailed by itemizing steps to follow both when coherent or noncoherent sampling is used. Finally, the procedure is applied to a 16-bit acquisition board and the theoretical and experimental standard deviations are compared in order to validate both the proposed estimation process and the effectiveness of the employed window sequences.

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The authors are with the Dipartimento di Ingegneria Elettronica e dell'Informazione, Perugia, Italy (e-mail: nunzi@diei.unipg.it).

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II. DFT-BASED METHOD

Spectral figures of merit usually employed for characterizing ADCs in the frequency domain are the spurious-free dynamic range (SFDR), the signal-to-noise-and-distortion-ratio (SINAD), the signal-to-random-noise-ratio (SRNR), and the total harmonic distortion (THD). They require the power estimation of the wide-band noise σ_R^2 and of $H + S + 1$ narrow-band components, $\sigma_{X_i}^2, i = 1, \dots, H + S + 1$, which are composed by the fundamental tone, H harmonics, and S spurious.

When noncoherent sampling applies, the DFT-based method evaluates the power of the narrow- and wide-band components from the windowed ADC output spectrum obtained by using a fast Fourier transform (FFT) algorithm. To this aim, as described in detail in [9], [10] and [11], the output spectrum is divided in sets of frequency bins, each associated with one kind of spectral component, indicated with \mathcal{B}_{X_i} for the narrow-band components and with \mathcal{B}_R for the wide-band noise.

Expressions for the power estimators of the wide-band noise, $\hat{\sigma}_R^2$, and of the i -th narrow-band component, $\hat{\sigma}_{X_i}^2$, are

$$\hat{\sigma}_R^2 \triangleq \frac{1}{N_R N^2} \frac{1}{\text{NNPG}} \sum_{k \in \mathcal{B}_R} |Y[k]|^2, \quad (1)$$

$$\hat{\sigma}_{X_i}^2 \triangleq \frac{2}{N^2} \frac{1}{\text{NNPG}} \sum_{k \in \mathcal{B}_{X_i}} |Y[k]|^2 - 2 \frac{N_{X_i}}{N} \hat{\sigma}_R^2. \quad (2)$$

In (1) and (2), N is the number of acquired samples, $Y[\cdot]$ is the DFT of the windowed acquired data samples, N_{X_i} is the number of samples in \mathcal{B}_{X_i} and N_R is the number of samples in \mathcal{B}_R . Moreover, $\text{NNPG} \triangleq (1/N) \sum_{n=0}^{N-1} w^2[n]$ is the window Normalized Noise Power Gain.

By defining $\hat{\sigma}_{X_1}^2, \hat{\sigma}_H^2 \triangleq \sum_{i=2}^{H+1} \hat{\sigma}_{X_i}^2$ and $\hat{\sigma}_S^2 \triangleq \sum_{i=H+2}^{S+1} \hat{\sigma}_{X_i}^2$ as the estimators of the power of the fundamental, of the harmonics and of the spurious components, respectively, the estimators of the spectral figures of merit are [10]

$$\widehat{\text{SRNR}} \triangleq \frac{N_R}{N_R + \text{ENBW}_0} \frac{\hat{\sigma}_{X_1}^2}{\hat{\sigma}_R^2} \quad (3)$$

$$\widehat{\text{SINAD}} \triangleq \frac{\hat{\sigma}_{X_1}^2}{\hat{\sigma}_R^2 + \hat{\sigma}_H^2 + \hat{\sigma}_S^2} \quad (4)$$

$$\widehat{\text{SFDR}} \triangleq \frac{\hat{\sigma}_{X_1}^2}{\max_{i>1} \hat{\sigma}_{X_i}^2} \quad (5)$$

$$\widehat{\text{THD}} \triangleq \frac{\hat{\sigma}_H^2}{\hat{\sigma}_{X_1}^2}, \quad (6)$$

where $\text{ENBW}_0 \triangleq N \sum_{n=0}^{N-1} w^4[n] / (\sum_{n=0}^{N-1} w^2[n])^2$ represents the equivalent-noise bandwidth of the squared window, $w^2[\cdot]$.

The accuracy of each estimator can be separately optimized by suitably choosing the test parameters and, in particular, by carefully selecting the window. The zero-order DPSS sequences can be employed to obtain maximum estimation accuracy [10]. However, the procedure for calculating their samples requires the application of iterating numerical algorithms, thus potentially reducing measurement reproducibility.

The class of windows considered in this paper is defined in the frequency domain on the basis of the Dirichelet kernel as follows [12]:

$$W[k, \Lambda] \triangleq \frac{\sin \left[\frac{N}{2} \cos^{-1}(\gamma \cos(2\pi k) + (\gamma - 1)) \right]}{\sin \left[\frac{1}{2} \cos^{-1}(\gamma \cos(2\pi k) + (\gamma - 1)) \right]}, \quad k = 0 \dots, N-1 \quad (7)$$

where $W[\cdot, \Lambda]$ represents the DFT of $w[\cdot]$, $\gamma \triangleq (1 + \cos(2\pi/N)) / (1 + \cos(2\Lambda\pi/N))$, and Λ is the window mainlobe width expressed in bins.

Such class of windows may easily be calculated from the knowledge of the record length N and of the needed mainlobe width Λ by using standard computational tools. Moreover, it has been demonstrated that they well approximates the zero-order DPSS sequences [12] with the same mainlobe width Λ . It follows that the window samples obtained by applying an inverse FFT (IFFT) algorithm to (7) assure optimal estimators accuracy, measurement reproducibility and testing automation.

In the next section, the related DFT-based testing procedure is step-by-step described. It allows the characterization of ADCs with any given resolution, by optimizing the available test-bench resources. In particular, indications for choosing the minimum number of samples which guarantees an upper bound, ε , on the relative type A uncertainty of the estimates of the spectral figures of merit, are explicitly given. Such bound has been derived by noticing that the normalized variance of the estimates of interest is equal to or lower than the normalized variance of (1), which is given by $\overline{\text{var}}\{\hat{\sigma}_R^2\} \simeq \text{ENBW}_0 / N_R$ [9], [10]. As a consequence, the number of samples associated to the wide-band noise has to satisfy the condition

$$N_R \geq \frac{\text{ENBW}_0}{\varepsilon^2}. \quad (8)$$

Moreover, indications for selecting the mainlobe window which guarantees optimum estimation accuracy is explicitly given.

III. PROPOSED PROCEDURE FOR ADC TESTING

Fig. 1 shows the steps to follow for estimating spectral parameters of a generic b -bit ADC with a given relative type A uncertainty ε . Grey boxes refer to calculations to be performed only when noncoherency applies. Whenever sampling is realized coherently, acquired data can be windowed by using a rectangular window and assuming $N_{X_i} = 1$.

The *algorithm input parameters* are related to both the characteristics of the measurement bench set-up and the device under test. The procedure requires knowledge of the maximum estimates accuracy, ε , the available memory-depth of the employed testing bench, N_{\max} , the operating full scale range (FS) of the device under test, its sampling rate f_s and an a priori estimate of the expected SRNR at the ADC output, γ_1 . If γ_1 is not available, the SRNR of an ideal b -bit quantizer can be employed.

The *data acquisition parameters* are then selected as follows: the number of acquired samples N_T , must satisfy the condition $N_T > \pi 2^b$ [1]. If $N_T > N_{\max}$ results, the testing algorithm can be repeatedly applied to R data records, each of length N , such that $RN \geq N_T$. Thus, the value of R can be calculated as

$R = \lceil N_T/N \rceil$, where the operator $\lceil x \rceil$ rounds x to the closest upper integer. The parameters of interest can then be derived by averaging the R resulting estimates. It should be noticed that the employed number of samples is often set to a power of two in order to reduce the FFT computational time.

If noncoherent sampling applies, an optimum *window parameter*, Λ_{opt} , can then be calculated as [10]

$$\Lambda_{\text{opt}} = 0.607 + 0.189 \log_{10} N_R + 0.378 \log_{10} \gamma_1 \quad (9)$$

where usually N_R can approximately be set equal to $N/3$. It is then possible to calculate the number of samples N_{X_i} associated to the estimate of each narrow-band component. The optimum value, obtained as a compromise between maximum estimator accuracy, maximum frequency selectivity and low computational effort, is [4]

$$N_{X_i} = 2\lceil \Lambda_{\text{opt}} \rceil + 1 \quad (10)$$

where the operator $\lceil x \rceil$ rounds x to the nearest integer.

In order to estimate accurately the narrow-band spectral components, it should be verified that the distance between the two closest components is greater than $2\lceil \Lambda_{\text{opt}} \rceil + 1$ bins. The condition to verify is then [10]

$$N > \frac{2\lceil \Lambda_{\text{opt}} \rceil + 1}{\min_{i \neq j} |f_{X_i} - f_{X_j}|} f_s, \quad i, j = 1, \dots, H + S + 1 \quad (11)$$

where f_{X_i} represents the frequency of the i -th narrow-band component expressed in Hz.

The window coefficients $w[\cdot]$ can then be calculated by substituting (9) in (7) and by applying the IFFT algorithm to the resulting expression.

Moreover, it should be verified that the total number of frequency bins associated to the $H + S + 1$ narrow-band components and to the wide-band noise do not exceed the number of available frequency bins, i.e., that

$$N_R \geq N - [2(H + S) + 1]N_{X_i}. \quad (12)$$

It should be also verified if the required estimator accuracy is guaranteed, that is if (8) occurs.

If (8), (11), or (12) are not satisfied, N must be increased. Whenever the number of samples needed to perform the test is greater than the available memory-depth, i.e., $N > N_{\text{max}}$, the test can not be carried out because of limits on hardware resources.

The *input sinewave parameters* are then set. In particular, the amplitude A has to be chosen in order not to overload the ADC; moreover, a proper frequency f_{in} has to be selected. In particular, whenever coherency must be attained, $f_{\text{in}} = f_s L/N$, where L is the integer number of acquired sinewave cycles which has to be chosen prime with respect to N .

Once the DFT-based algorithm parameters have been set, it is possible to proceed with the estimation of the desired ADC spectral parameters based on the r -th data record. In particular, the powers of the wide- and narrow-band components, $\hat{\sigma}_{R_r}^2$ and $\hat{\sigma}_{X_{i_r}}^2$, are evaluated by using (1) and (2), respectively. Finally, (3)–(6) can be applied to estimate the corresponding figures of merit. The overall ADC spectral performances can then be eval-

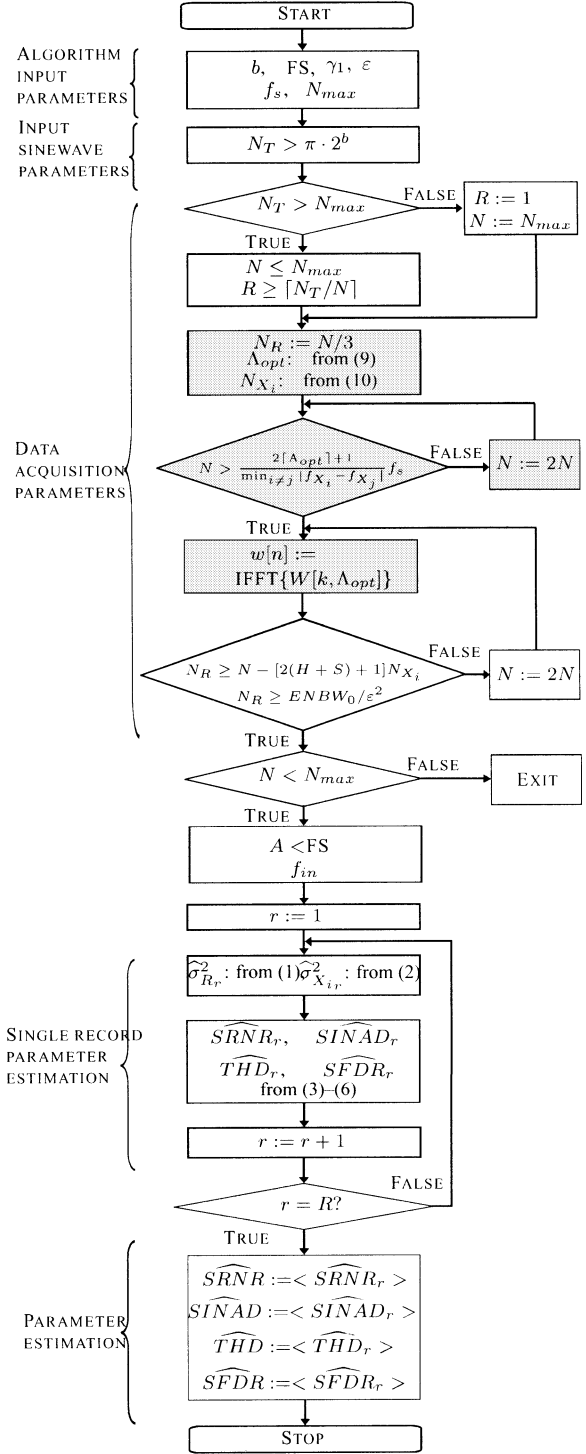


Fig. 1. Flow chart of the DFT-based testing algorithm. Gray boxes indicate calculations to be performed only when noncoherent sampling applies. N is set to a power of two in order to apply classical FFT algorithms to the windowed data.

uated by taking the arithmetic average over R records, as indicated in Fig. 1 by the operator $\langle x_r \rangle \triangleq 1/R \sum_{r=1}^R x_r$.

IV. EXPERIMENTAL RESULTS

The algorithm described in Section III has been applied to data acquired from the 16-bit data acquisition board AT-MIO-

TABLE I
ALGORITHM PARAMETERS EMPLOYED FOR
OBTAINING EXPERIMENTAL RESULTS OF FIG. 2

Algorithm input parameters	<i>b</i>	<i>FS</i>	<i>f_s</i>	<i>ε²</i>
	16	10 V	20 ksample/s	$2 \cdot 10^{-4}$
Input sinewave parameters	<i>A</i>	<i>f_{in}</i>	<i>γ₁</i> ideal	
	9.85 V	variable	97.96 dB	
Data acquisition parameters	<i>N=N_{max}</i>	<i>N_T</i>	<i>N_R</i>	<i>R</i>
	2^{14}	2^{18}	14448	100
Window parameters	<i>Δ_{opt}</i>	<i>NNPG</i>	<i>ENBW₀</i>	<i>N_{X1}</i>
	5.02	0.23	3.14	11

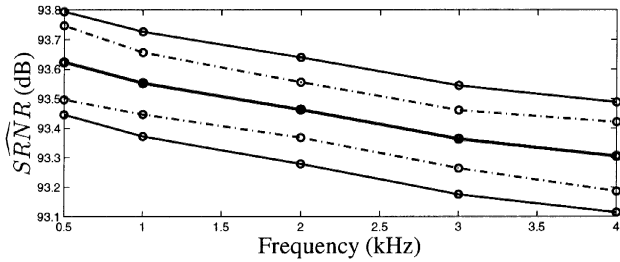


Fig. 2. Bold line represents the \widehat{SRNR} of the AT-MIO-16-XE-50 data acquisition board estimated with the DFT-based algorithm by employing parameters shown in Table II and the proposed window (7). Solid and dash-dotted lines represent the average plus and minus the theoretical and experimental standard deviations, respectively.

16XE-50, developed by National Instruments, for evaluating the SRNR at various input frequency values. Such a board has a sampling rate of 20 ksample/s and a full-scale range equal to ± 10 V. The signal generator used as input stimulus is the Stanford Research System DS360 generator, which exhibits an SFDR larger than 96 dBc. The amplitude of the input sinewave has been set equal to 9.85 V, the value at which the maximum SRNR has been experimentally obtained by employing a 1 kHz input sinewave. The corresponding γ_1 value is 97.96 dB. The energy-based algorithm has been applied for input frequencies equal to 0.5, 1, 2, 3, and 4 kHz, and the SRNR has been estimated.

The algorithm parameters employed for the specific case are reported in Table I and the various SRNR estimates have been graphed in Fig. 2. In particular, the bolded line represents the average based on $R = 100$ data records, and dash-dotted lines represent the SRNR plus and minus the experimental standard deviation.

In order to validate the proposed procedure, the value of the theoretical standard deviation of \widehat{SRNR} have been calculated by means of [11]

$$\text{std}\{\widehat{SRNR}\} = \sqrt{\frac{ENBW_0}{N_R}} \gamma_1. \quad (13)$$

The experimental SRNR plus and minus such a theoretical standard deviation has been also plotted in Fig. 2 with solid lines. The good agreement between the experimental and the theoretical lines confirms the effectiveness of the testing procedure and of the proposed class of windows.

It should be noticed that estimate accuracy achieved by using the class of windows proposed in this paper has the same order magnitude of that attainable by employing windows suggested by the classical scientific literature [3]. The advantage in using this new class of windows is that (7) can be employed for testing ADCs with any given resolution by setting only the Δ parameter.

V. CONCLUSION

The problem of optimizing the accuracy of the ADCs spectral figures of merit when noncoherent sampling applies, is not thoroughly investigated by the published scientific literature [1]–[3], [7]. In particular, the lack of a criterion for choosing the window which guarantees, for a given b -bit ADC, the maximum estimator accuracy, reduces measurement reproducibility.

In order to overcome this limitation, in this paper a DFT-based ADC testing algorithm has been detailed from a procedural point of view. Accordingly, it has been proposed the use of a class of windows that are completely characterized by setting only the mainlobe width value and that can be employed for testing any given resolution ADC. In order to improve measurement accuracy, a criterion for selecting the optimum window mainlobe width has been provided. Whenever coherent sampling can be attained, the proposed method can still be applied to un-windowed data.

The procedure has been used to measure the performance of a 16-bit data-acquisition board and experimental results, which validate both the testing method and the employed windows, have been presented.

REFERENCES

- [1] *Standard for Digitizing Waveform Recorders*, Dec. 1994. IEEE Std. 1057.
- [2] *Standard for Terminology and Test Methods for Analog-to-Digital Converters*, Oct. 2000. IEEE Std. 1241.
- [3] O. M. Solomon Jr., "The use of DFT windows in signal-to-noise ratio and harmonic distortion computations," *IEEE Trans. Instrum. Meas.*, vol. 43, pp. 194–199, Apr. 1994.
- [4] P. Carbone, E. Nunzi, and D. Petri, "Windows for ADC dynamic testing via frequency-domain analysis," *IEEE Trans. Instrum. Meas.*, vol. 50, pp. 1679–1683, Dec. 2001.
- [5] S. L. Marple Jr., *Digital Spectral Analysis with Applications*. Englewood Cliffs, NJ: Prentice-Hall, 1987.
- [6] I. Kollár, "Evaluation of sinewave tests of ADC's from windowed data," in *Proc. 4-th Int. Workshop ADC Modeling and Testing*, Bordeaux, France, Sept. 9–10, 1999, pp. 64–68.
- [7] Methods and Draft Standards for the DYNAMIC Characterization and Testing of Analogue to Digital Converters [Online]. Available: <http://www.fe.up.pt/hsm/dynad>
- [8] D. Slepian, "Prolate spheroidal wave functions, fourier analysis and uncertainty—V: The discrete case," *Bell Syst. Tech. J.*, vol. 57, pp. 1371–1430, May–June 1978.
- [9] P. Carbone, E. Nunzi, and D. Petri, "Characterization of a data acquisition system in a remotely controlled environment," in *Proc. 11th IMEKO TC 4, 6th EuroWorkshop ADC Modeling and Testing*, Lisbon, Portugal, Sept. 13–14, 2001, pp. 66–70.
- [10] P. Carbone and D. Petri, "Effective frequency-domain ADC testing," *IEEE Trans. Circuits Syst.—II: Analog Digital Signal Processing*, vol. 47, pp. 660–663, July 2000.
- [11] D. Petri, "Frequency-domain testing of waveform digitizers," *IEEE Trans. Instrum. Meas.*, vol. 51, pp. 445–453, June 2002.
- [12] T. Saramaki, "Adjustable windows for the design of FIR filter—A tutorial," in *Proc. 6th Mediterranean Electrotechnical Conf.*, vol. 1, 1991, pp. 28–33.



Emilia Nunzi received the Laurea degree and the Dottorato di Ricerca degree in electronics engineering from the University of Perugia, Perugia, Italy, in 1997 and 2000, respectively.

Since 2000, she has been a Contract Researcher at the Dipartimento di Ingegneria Elettronica e dell'Informazione, University of Perugia. Her research interests are error modeling of mismatching in Delta-Sigma converters and electronics measurements fields, with specific concern to the frequency domain ADC testing procedures.



Paolo Carbone (A'95) received the Engineer's degree and the Dottorato di Ricerca degree from the University of Padova, Padova, Italy in 1990 and 1994, respectively.

From 1994 to 1997, he was a Researcher at the Third University of Roma, Rome, Italy, and, since 1997, at the University of Perugia, Perugia, Italy. From November 2000 until November 2002, he was Associate Professor of electronic measurements at the University of Perugia. Since November 2002, he has been a Full Professor in the same scientific area,

at the University of Perugia. His research objective is to develop knowledge, models, and systems for the advancement of the instrumentation and measurement technology. The research involves the development of original techniques for signal acquisition analysis and interpretation. The emphasis of the research is on the improvement of the performance of electronic instrumentation and data acquisition systems using state-of-the-art technologies.

Prof. Carbone is an AEI member and Associate Editor for the IEEE TRANSACTIONS ON CIRCUITS AND SYSTEMS II.

Dario Petri (M'92) received the Laurea degree and the Ph.D. degree in electronic engineering from the University of Padova, Padova, Italy, in 1986 and 1990, respectively.

From 1990 to 1992, he was with the Dipartimento di Ingegneria Elettronica e Informatica, University of Padova, as a Research Fellow. Then he joined the Dipartimento di Ingegneria Elettronica e dell'Informazione, University of Perugia, Perugia, Italy, in 1992 as an Associate Professor, teaching courses on instrumentation and digital electronic systems. From 1999 to 2002, he was a Full Professor of measurement and electronic instrumentation at the same Department and the Chairperson of the undergraduate and graduate degree study programs in information engineering. At present, he is a Full Professor of electronic measurement at the Dipartimento di Informatica e Telecomunicazioni, University of Trento, Trento, Italy. He also coordinates the national Ph.D. summer school on measurement and information society and the research line on measurement for the information society, both within the Italian Group of Electrical and Electronic Measurement. He is author and coauthor of almost 100 papers published in international journals or in proceedings of international congresses. He is also a reviewer for several international journals in the field of instrumentation and electronic systems. His research activities are in the general areas of measurement science and technology, with particular interest in data acquisition systems design and testing, digital electronic systems design and characterization, management of system performance, application of digital signal processing, and statistical parameter estimation methods to measurement problems.

Dr. Petri is a member of AEI.